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(54) **Title**: SYSTEM FOR TESTING SEMICONDUCTORS

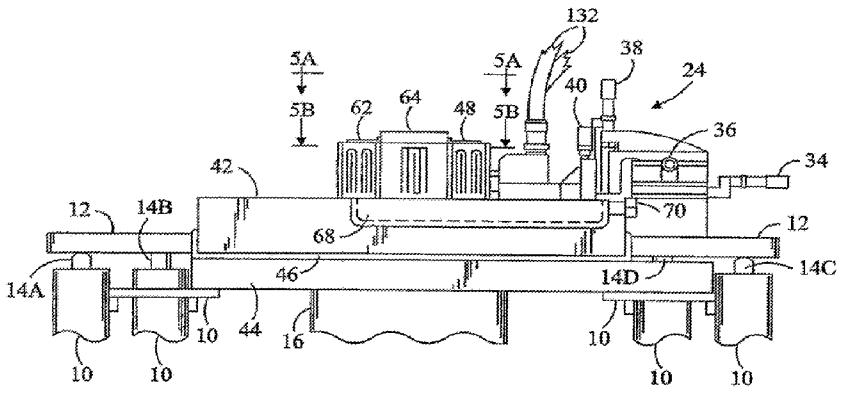


FIG. 1

(57) **Abstract**: A system that includes an imaging device for effectively positioning a probe for testing a semiconductor.

WO 2011/113051 A1